

REMARKS

It is respectfully requested that the above amendments be entered before the claims are considered by the Examiner.

Respectfully submitted,

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Dated: 9/28/01

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APPENDIX

MARKED UP VERSION OF VERSION OF AMENDED CLAIMS

In the Claims:

3. (Amended) Tool according to Claim 1 [or 2], characterized in that the second carbon layer (B) is deposited directly on the first carbon layer (A).
4. (Amended) Tool according to Claim 1 [or 2], characterized in that formed between the first carbon layer (A) and the second carbon layer (B) is an interlayer in the case of which the fraction of carbon with a diamond crystal structure drops continuously from the first carbon layer (A) in the direction of the second carbon layer (B).
5. (Amended) Tool according to Claim 1 [one of Claim 1 to 4], characterized in that it has an overall thickness of the first carbon layer (A) and the second carbon layer (B) in the range from 1 to 40 μm .
8. (Amended) Tool according to Claim 1 [one of Claims 1 to 7], characterized in that the second carbon layer (B) has a minimum thickness of 0.5 μm .
10. (Amended) Tool according to Claim 1 [one of Claims 1 to 9], characterized in that with reference to the substrate beyond the second carbon layer further material layers are arranged.
12. (Amended) Process according to Claim 11 [10], in which in step a) the process conditions are selected such that the first carbon layer (A) has as high as possible a fraction of carbon with diamond crystal structure.
13. (Amended) Process according to Claim 11 [or 12], in which in step b) the process conditions of step a) are changed to reduce the fraction of carbon with a diamond crystal structure by comparison with the first carbon layer (A).